

IGBT

TRENCHSTOP[™] IGBT3 Chip IGC114T170S8RM

Data Sheet

Industrial Power Control



IGC114T170S8RM

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TRENCHSTOP[™] IGBT3 Chip

Features:

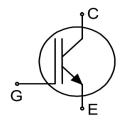
- 1700V trench & field stop technology
- Low switching losses
- Soft turn off
- Positive temperature coefficient
- Easy paralleling

Recommended for:

• Power modules

Applications:

Drives



Chip Type	V _{CE}	I Cn ¹	Die Size	Package
IGC114T170S8RM	1700V	100A	9.47mm x 12.08mm	Sawn on foil

Mechanical Parameters

Die size		9.47 x 12.08		
Emitter pad size		See chip drawing	mm ²	
Gate pad size		1.674 x 0.899	mm	
Area total		114.4		
Thickness		190	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	225		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500µm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2 <6 months	25°C,	
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or humidity <25%RH, temperature 17°C – 25°C, <6		

¹ Nominal collector current at T_{C} =100°C for chip packaged in power modules, see application example cited on page 5.



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-emitter voltage, <i>T</i> _{vj} =25°C	V _{CE}	1700	V	
DC collector current, limited by $T_{\rm vjmax}^2$	I _C	-	Α	
Pulsed collector current, t_p limited by $T_{vj max}^3$	I _{C,puls}	300	А	
Gate-emitter voltage	V _{GE}	±20	V	
Junction temperature range	T _{vj}	-40 +175	°C	
Operating junction temperature	T _{vj}	-40 +150	°C	
Short circuit data $^{3/4}$ V _{GE} =15V, V _{CC} =1000V, T _{vj} =150°C	t _{sc}	10	μs	
Reverse bias safe operating area ³ (RBSOA)	<i>I</i> _{C,max} =200A, <i>V</i> _{CE,max} =1700V, <i>T</i> _{vj} ≤150°C			

Static Characteristics (tested on wafer), Tvi=25°C

Parameter	Symbol	Conditions	Value			Unit
Farameter			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	<i>V</i> _{GE} =0V, <i>I</i> _C =2mA	1700	-	-	
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, <i>I</i> _C =100A	1.6	1.9	2.2	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_{\rm C}$ =4mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.2	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V _{CE} =1700V, V _{GE} =0V	-	-	5.6	μA
Gate-emitter leakage current	I _{GES}	V_{CE} =0V, V_{GE} =20V	-	-	300	nA
Integrated gate resistor	r _G			7.5		Ω

Electrical Characteristics ³

Parameter	Symbol	Conditions	Value			110:4
	Symbol		min.	typ.	max.	Unit
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, <i>I</i> _C =100A, <i>T</i> _{vj} =150°C	-	2.45	-	V
Input capacitance	C _{ies}	$V_{\rm CE}=25V,$	-	9000	-	~~
Reverse transfer capacitance	C _{res}	V _{GE} =0V, <i>f</i> =1MHz <i>T</i> _{vj} =25°C	-	290	-	pF

 ² Depending on thermal properties of assembly.
³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

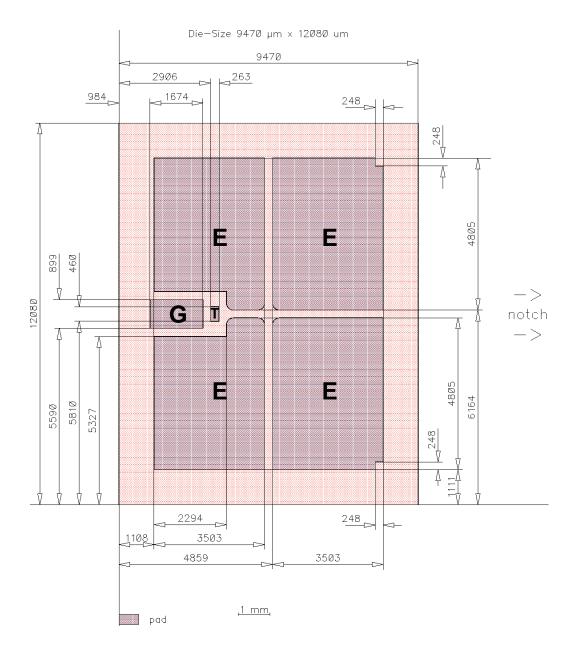
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FS100R17PE4	Rev. 2.1
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IGC114T170S8RM

Chip Drawing



- E = Emitter
- G = Gate
- T = Test pad do not contact



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

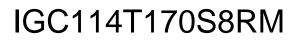
Description

AQL 0.65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	06.02.2015
2.1	Update disclaimer	19.08.2015

Relevant Application Notes





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